

## Refine Search

### Search Results -

Terms	Documents
(calculat\$5 near3 (fault\$1 near3 coverage\$1))and L21	4

Database:

US Pre-Grant Publication Full-Text Database  
 US Patents Full-Text Database  
 US OCR Full-Text Database  
 EPO Abstracts Database  
 JPO Abstracts Database  
 Derwent World Patents Index  
 IBM Technical Disclosure Bulletins

Search:

L22



Refine Search

Recall Text



Clear

Interrupt

### Search History

DATE: Wednesday, August 16, 2006   [Printable Copy](#)   [Create Case](#)

#### Set Name Query

side by side

#### Hit Count

#### Set Name

result set

*DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ*

<u>L22</u>	(calculat\$5 near3 (fault\$1 near3 coverage\$1))and L21	4	<u>L22</u>
<u>L21</u>	(delay fault\$1) same (simulat\$5)	94	<u>L21</u>
<u>L20</u>	(delay fault\$1) same (longest near3 (signal path\$1))	1	<u>L20</u>
<u>L19</u>	l16 and L18	24	<u>L19</u>
<u>L18</u>	(delay fault\$1) same test\$5	374	<u>L18</u>
<u>L17</u>	(delay fault\$1) and test\$5	496	<u>L17</u>
<u>L16</u>	l8 and L15	34	<u>L16</u>
<u>L15</u>	semiconductor\$1 and L14	42	<u>L15</u>
<u>L14</u>	(delay fault\$1) and (signal path\$1)	80	<u>L14</u>
<u>L13</u>	l9 or L12	31	<u>L13</u>
<u>L12</u>	l8 and L11	20	<u>L12</u>
<u>L11</u>	l5 or l4 or l1 or L10	37	<u>L11</u>
<u>L10</u>	l3 and L6	26	<u>L10</u>
<u>L9</u>	l7 and L8	17	<u>L9</u>

<u>L8</u>	@ad<20030130	23609011	<u>L8</u>
<u>L7</u>	l2 and L6	30	<u>L7</u>
<u>L6</u>	714/\$.ccls.	55413	<u>L6</u>
<u>L5</u>	(delay fault\$1) near4 (calculat\$5)	16	<u>L5</u>
<u>L4</u>	(delay fault\$1) near4 (calculat\$5 near4 coverage\$1)	4	<u>L4</u>
<u>L3</u>	(delay fault\$1) near4 (deci\$5 or coverage\$1)	51	<u>L3</u>
<u>L2</u>	(delay fault\$1) near4 (defin\$5 or select\$5)	55	<u>L2</u>
<u>L1</u>	(delay fault\$1) near4 (evaluat\$5 near4 quality)	6	<u>L1</u>

END OF SEARCH HISTORY